MOSFET - Power, Single, N-Channel, DPAK/IPAK 30 V, 63 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These are Pb-Free Devices

Applications

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

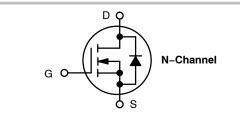
Par	ameter		Symbol	Value	Unit
Drain-to-Source Vo	n-to-Source Voltage			30	V
Gate-to-Source Vol	tage		V_{GS}	±20	V
Continuous Drain Current R _{BJA}		T _A = 25°C	I _D	13.8	Α
(Note 1)		T _A = 85°C		10.7	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P_D	2.63	W
Continuous Drain Current R _{0.1A}		T _A = 25°C	ID	10	Α
(Note 2)	Steady State	T _A = 85°C		7.8	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	1.4	W
Continuous Drain Current R _{BJC}		T _C = 25°C	I _D	63	Α
(Note 1)		T _C = 85°C		49	
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P _D	54.6	W
Pulsed Drain Current	t _p =10μs	T _A = 25°C	I _{DM}	126	Α
Current Limited by P	ackage	T _A = 25°C	I _{DmaxPkg}	45	Α
Operating Junction and Storage Temperature		T _J , T _{STG}	–55 to +175	ç	
Source Current (Body Diode)			I _S	45	Α
Drain to Source dV/dt			dV/dt	6	V/ns



ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
20.14	8.0 mΩ @ 10 V	
30 V	12.4 mΩ @ 4.5 V	63 A



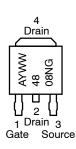


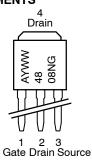




IPAK CASE 369D STYLE 2

MARKING DIAGRAMS & PIN ASSIGNMENTS





A = Assembly Location*

Y = Year

WW = Work Week

4808N = Device Code

G = Pb-Free Package

* The Assembly Location code (A) is front side optional. In cases where the Assembly Location is stamped in the package, the front side assembly code may be blank.

ORDERING INFORMATION

See detailed ordering and shipping information on page 6 of this data sheet.

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter	Symbol	Value	Unit
Single Pulse Drain-to-Source Avalanche Energy (V_{DD} = 24 V, V_{GS} = 10 V, I_L = 17 A_{pk} , L = 1.0 mH, R_G = 25 Ω)	EAS	144.5	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)	TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.75	
Junction-to-TAB (Drain)	$R_{ heta JC-TAB}$	3.5	0000
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	57	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	107	

- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T_{.I} = 25°C unless otherwise specified)

Parameter	Symbol	Test Condi	tion	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•			•	•	•	•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0 V, I _D =	250 μΑ	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /				27		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	T _J = 25 °C			1	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D =$: 250 μA	1.5		2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5.6		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 to 11.5 V	I _D = 30 A		6.7	8.0	
			I _D = 15 A		6.6		mΩ
		V _{GS} = 4.5 V	I _D = 30 A		10.3	12.4	
			I _D = 15 A		9.8		
Forward Transconductance	9 _{FS}	V _{DS} = 15 V, I _D	= 15 A		11.4		S
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				1538		
Output Capacitance	Coss	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 12 V			334		pF
Reverse Transfer Capacitance	C _{RSS}				180		1

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 3. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 4. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified) (continued)

Parameter	Symbol	Test Condit	ion	Min	Тур	Max	Unit
CHARGES AND CAPACITANCES	•	•					
Total Gate Charge	$Q_{G(TOT)}$	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			11.3	13	
Threshold Gate Charge	Q _{G(TH)}				1.6		.0
Gate-to-Source Charge	Q_{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 1.5 \text{ V}$	5 V; I _D = 30 A		4.9		nC
Gate-to-Drain Charge	Q_{GD}				4.9		1
Total Gate Charge	$Q_{G(TOT)}$	V _{GS} = 11.5 V, V _{DS} = 15 V; I _D = 30 A			26		nC
SWITCHING CHARACTERISTICS (N	lote 4)	•					
Turn-On Delay Time	t _{d(ON)}				12.3		
Rise Time	t _r	V _{GS} = 4.5 V, V _{DS} = 15	i V, I _D = 15 A,		21.3		- ns
Turn-Off Delay Time	t _{d(OFF)}	V _{GS} = 4.5 V, V _{DS} = 15 R _G = 3.0 9	Ω		14.6		
Fall Time	t _f				6.0		1
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 11.5 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			7.7		
Rise Time	t _r				19.5		ns
Turn-Off Delay Time	t _{d(OFF)}				23		
Fall Time	t _f				3.5		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V _{SD}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$		0.93	1.2	\ /
		I _S = 30 A	T _J = 125°C		0.83		V
Reverse Recovery Time	t _{RR}				20		
Charge Time	t _a	$V_{GS} = 0 \text{ V, dI}_S/\text{dt} =$	100 A/μs,		10.4		ns
Discharge Time	t _b	$V_{GS} = 0 \text{ V, dI}_{S}/\text{dt} = I_{S} = 30 \text{ A}$	١, ٠		9.6		
Reverse Recovery Charge	Q _{RR}	1			9.7		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L _S				2.49		nH
Drain Inductance, DPAK	L _D	T _A = 25°C			0.0164		
Drain Inductance, IPAK	L _D				1.88		
Gate Inductance	L _G	1			3.46		
Gate Resistance	R_{G}				1.1		Ω

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

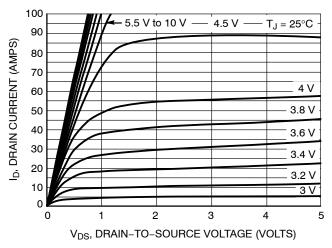
3. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

^{4.} Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

80

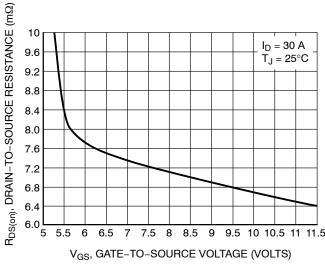
 $V_{DS} \ge 10 \text{ V}$



70 DRAIN CURRENT (AMPS) 60 50 40 30 T_J = 125°C 20 $T_J = 25^{\circ}C$ ث 10 $T_J = -55^{\circ}C$ 0 2 3 5 V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



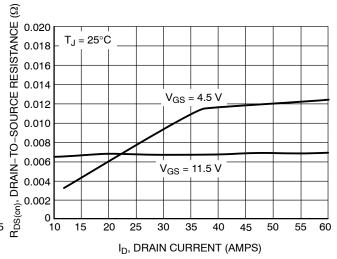
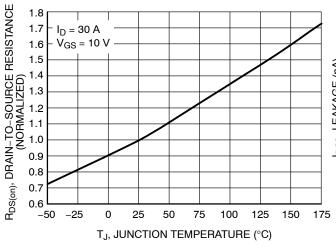


Figure 3. On–Resistance vs. Gate–to–Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



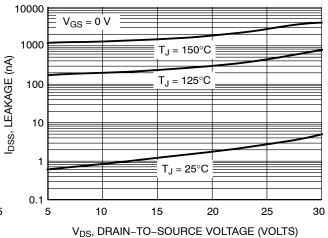
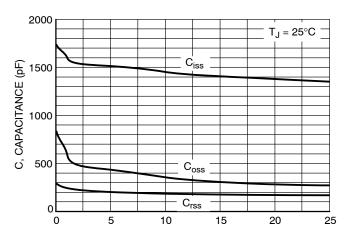


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Drain Voltage

TYPICAL PERFORMANCE CURVES



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

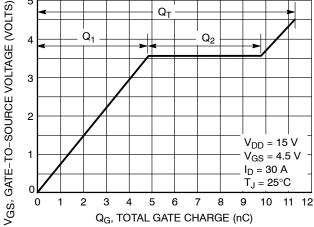


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge



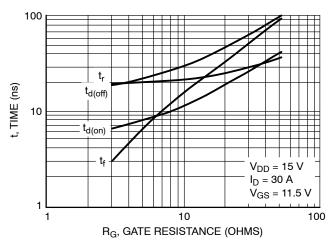


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

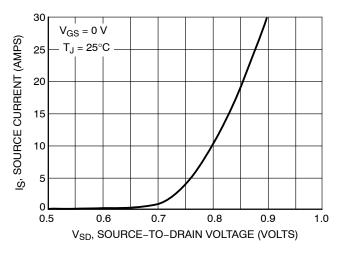


Figure 10. Diode Forward Voltage vs. Current

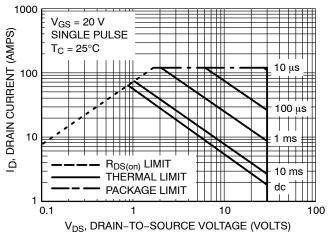


Figure 11. Maximum Rated Forward Biased Safe Operating Area

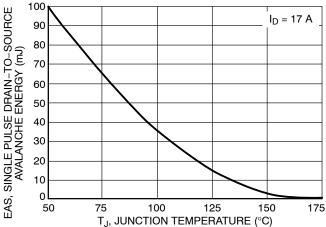


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL PERFORMANCE CURVES

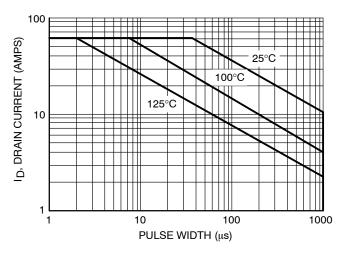


Figure 13. Avalanche Characteristics

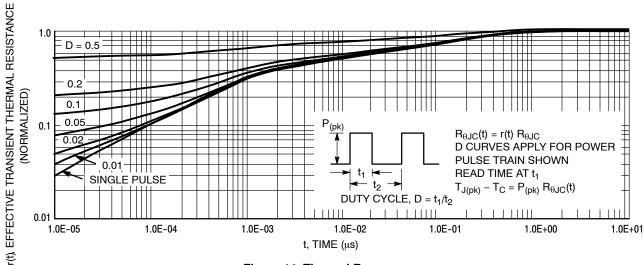


Figure 14. Thermal Response

ORDERING INFORMATION

Device	Package	Shipping [†]
NTD4808NT4G	DPAK (Pb-Free)	2500 / Tape & Reel
NTD4808N-1G	IPAK (Pb-Free)	75 Units / Rail
NVD4808NT4G*	DPAK (Pb-Free)	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

^{*}NVD Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable.

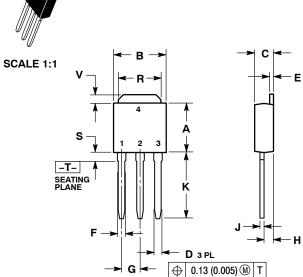
MECHANICAL CASE OUTLINE

PACKAGE DIMENSIONS





DATE 15 DEC 2010



STYLE 2:

PIN 1. GATE

3

STYLE 6: PIN 1. MT1 2. MT2 3. GATE

2. DRAIN

4. DRAIN

MT2

SOURCE

STYLE 1: PIN 1. BASE

3

STYLE 5: PIN 1. GATE

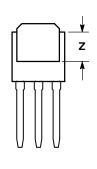
2. ANODE 3. CATHODE

ANODE

2. COLLECTOR

EMITTER

COLLECTOR



NOTES:

- DIMENSIONING AND TOLERANCING PER
 ANSI V14 5M 1992
- ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.235	0.245	5.97	6.35
В	0.250	0.265	6.35	6.73
С	0.086	0.094	2.19	2.38
D	0.027	0.035	0.69	0.88
E	0.018	0.023	0.46	0.58
F	0.037	0.045	0.94	1.14
G	0.090	BSC	2.29	BSC
Н	0.034	0.040	0.87	1.01
J	0.018	0.023	0.46	0.58
K	0.350	0.380	8.89	9.65
R	0.180	0.215	4.45	5.45
S	0.025	0.040	0.63	1.01
٧	0.035	0.050	0.89	1.27
Z	0.155		3.93	

MARKING DIAGRAMS

STYLE 4:
PIN 1. CATHODE
2. ANODE
3. GATE
4. ANODE

STYLE 3: PIN 1. ANODE

2. CATHODE

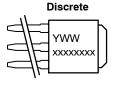
4. CATHODE

3 ANODE

STYLE 7: PIN 1. GATE 2. COLLECTOR

3. EMITTER

COLLECTOR





xxxxxxxxx = Device Code
A = Assembly Location
IL = Wafer Lot
Y = Year
WW = Work Week

DOCUMENT NUMBER:	98AON10528D Electronic versions are uncontrolled except when accessed directly from the printed versions are uncontrolled except when stamped "CONTROLLED CONTROLLED		
DESCRIPTION:	IPAK (DPAK INSERTION MOUNT)		PAGE 1 OF 1

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STYLE 1: PIN 1. BASE

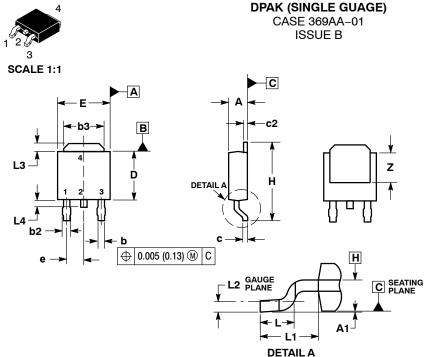
STYLE 5:

2. COLLECTOR 3. EMITTER

4. COLLECTOR

PIN 1. GATE 2. ANODE 3. CATHODE

4. ANODE



STYLE 3: PIN 1. ANODE

STYLE 7:

2. CATHODE 3. ANODE

PIN 1. GATE 2. COLLECTOR

3. EMITTER

COLLECTOR

CATHODE



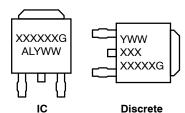
DATE 03 JUN 2010

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: INCHES.
 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-MENSIONS b3, L3 and Z.
 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD
- FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 6. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.030	0.045	0.76	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090	BSC	2.29 BSC	
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.108	0.108 REF		REF
L2	0.020 BSC		0.51	BSC
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	

GENERIC MARKING DIAGRAM*



XXXXXX = Device Code Α = Assembly Location L = Wafer Lot ٧ = Year = Work Week WW = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

SOLDERING FOOTPRINT*

STYLE 2: PIN 1. GATE

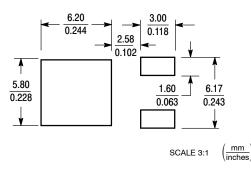
STYLE 6:

PIN 1. MT1 2. MT2

3. GATE

2. DRAIN 3. SOURCE

4. DRAIN



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	DPAK (SINGLE GAUGE)		PAGE 1 OF 1

ROTATED 90° CW

STYLE 4: PIN 1. CATHODE 2. ANODE 3. GATE

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